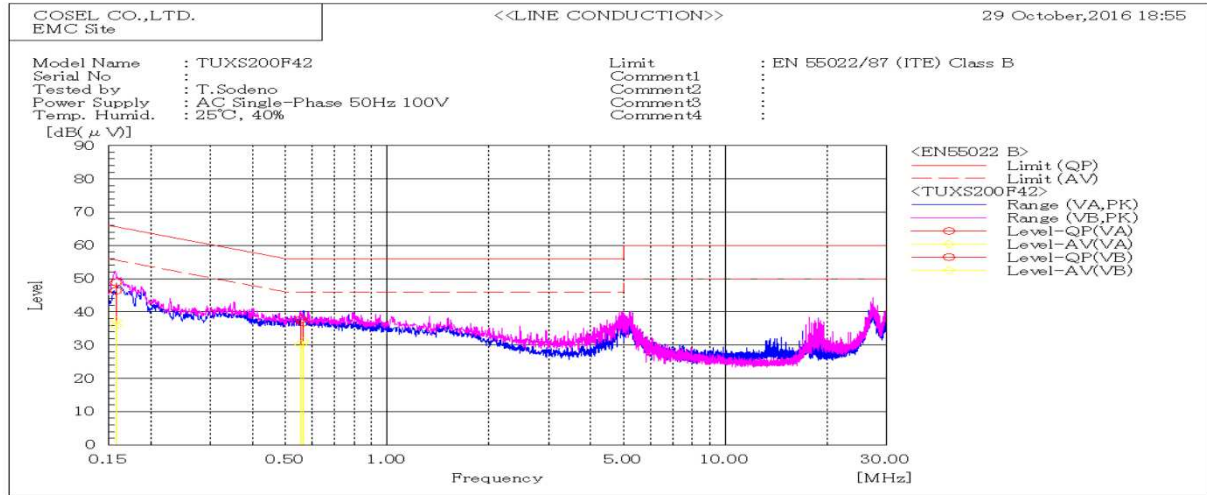
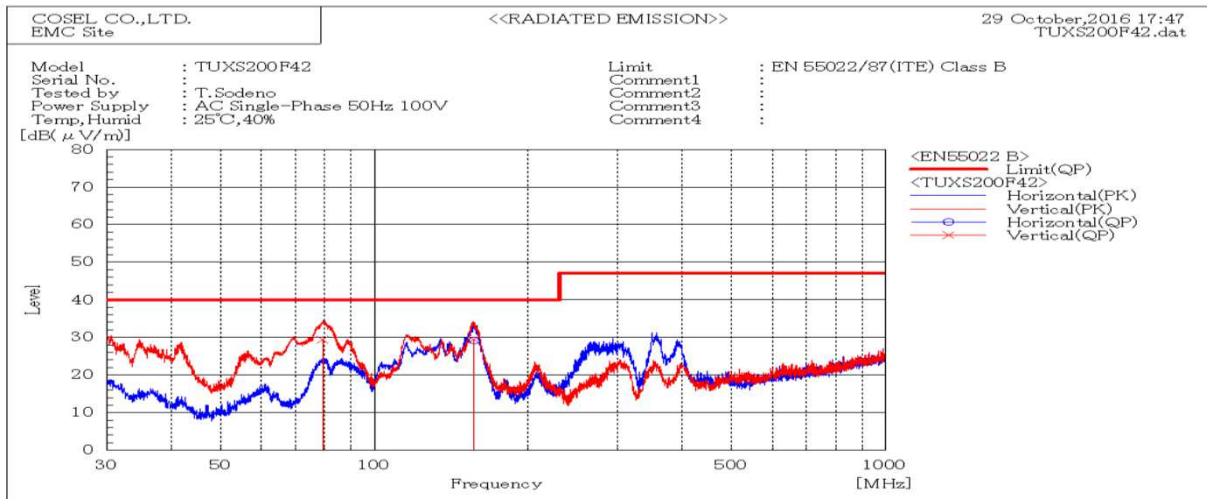


DATA SHEET		Date	31-Oct-16
Model	TUXS200F42	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno



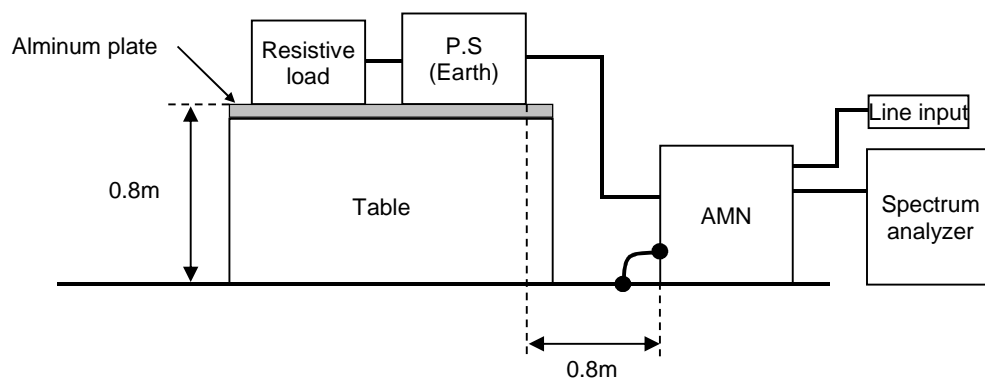
Frequency MHz	Line Phase	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail
		QP	AV	QP	AV	QP	AV	
0.15756	VB	48.9	37.3	65.6	55.6	16.7	18.3	Pass
0.15748	VA	46.3	35.9	65.6	55.6	19.3	19.7	Pass
0.55448	VB	37.8	30.2	56	46	18.2	15.8	Pass
0.56568	VA	36.8	31.2	56	46	19.2	14.8	Pass



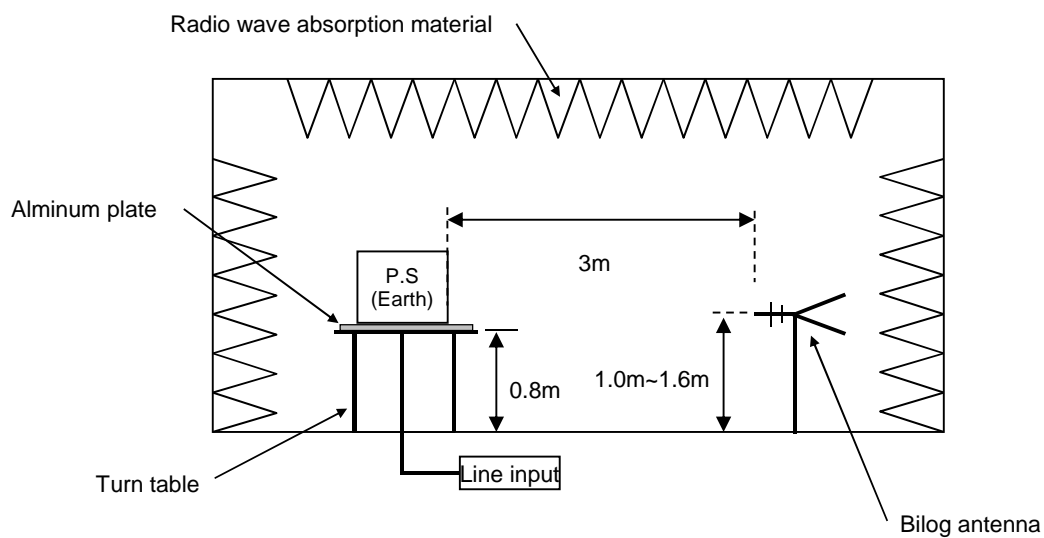
Frequency MHz	Polarization	Stability	Reading dB(uV)	Limit dB(uV/m)	Margin dB(uV/m)	Pass/Fail	Height cm	Angle deg
			QP	QP	QP			
79.245	V	Stable	29.4	40.0	10.6	Pass	120	262
156.237	V	Stable	29.5	40.0	10.5	Pass	138	144
156.735	H	Stable	29.1	40.0	10.9	Pass	159	189

DATA SHEET		Date	31-Oct-16
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sodeno

## 1. Line conduction



## 2. Radiated emission



Test: EMI

Model Name:TUXS200F42

○ Photographs of Test Set-Up

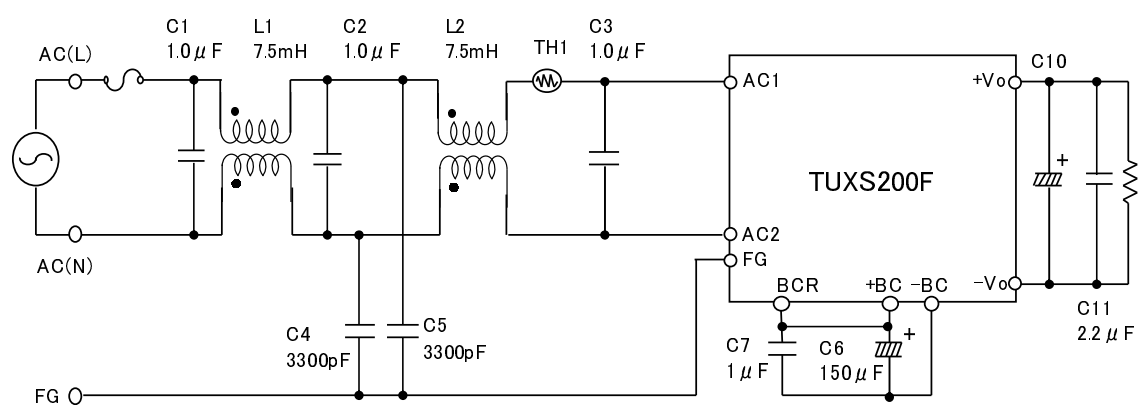
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1,L2 : SCR22-060-1R0A075JH(NEC TOKIN)
- TH1 : 12D2-11LC(SEMITEC)
- C1,C2,C3 : LE105-MX(OKAYA)
- C4,C5 : DE1E3KX332M(MURATA)
- C6 : EKXJ421ELL151MM50S(Nippon Chemi-con)
- C7 : AFS450V105K(OKAYA)
- C10 : PCR1J101MCL1GS(NICHICON) × 3
- C11 : GRM31CR72A225K(MURATA)